

DL1100e

Logic Burn-In Tester

DL series provide advanced Package Burn-in Test for Logic Device IC's. With its Multi-Controllable temperature zones and pattern zones, users will have flexible environment to test different kinds of products at the same time.

- Frequency : 10Mhz (10ns Resolution)
- Channel : 256 I/O + 18 Scan
- Pattern Zone : 4 zones / Chamber (Basic) /
32 zones / Chamber (Option)
- Device
DL1100e : Logic, SoC, CIS, LDI, Smart Card
- Temperature Zone : 2 Chambers (Hot & Cold)
- Temperature : -40 °C ~ +150 °C
- Endurance Test : Yes
- Multizone Test Function : Yes
- DPS (User Cusomizing) 5PS /BIB
+50V / 20 A x 1PS
+100V / 30 A x 1PS
-20V / 10A x 1PS
+10V / 10A x 2PS



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